IN THE CLAIMS

Please amend claim 1 as follows:

1. (Amended) A quality assurance automatic display system comprising:

a data processor having an inspection item data hold section and a data processing section;

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the inspection item data hold section holding inspection item graded data which have been graded by determination of reliability of a per-inspection-item for a substance to be inspected; and

the data processing section determining general graded data pertaining to the degree of quality assurance of the substance in accordance with an algorithm employed in the data processing section after having received the inspection item graded data from the inspection item data hold section; and

a display device for displaying, for an individual semiconductor device that has been inspected, the general graded data transported from the data processing section, thereby indicating the degree of quality assurance of the inspected individual semiconductor device.

REMARKS

Claims 1 through 6 are pending in this application. These claims as originally presented have been rejected in the Office Action dated January 30, 2003. Amendments are made herein to the specification and to claims 1 and 6. Filed herewith is a request for approval of a drawing correction to Figs. 1 and 5, as shown in red on an attached